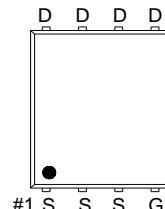
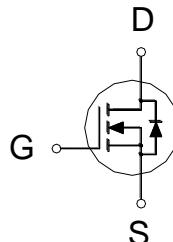


NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P3710BK**
PDFN 5x6P
Halogen-Free & Lead-Free**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	37mΩ	24A

G. GATE
D. DRAIN
S. SOURCE**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	24	A
	$T_C = 100^\circ\text{C}$		15	
Pulsed Drain Current ¹		I_{DM}	50	A
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	6	
	$T_A = 70^\circ\text{C}$		5	
Avalanche Current		I_{AS}	16	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	128	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	50	W
	$T_C = 100^\circ\text{C}$		20	
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	2.7	W
	$T_A = 70^\circ\text{C}$		1.7	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

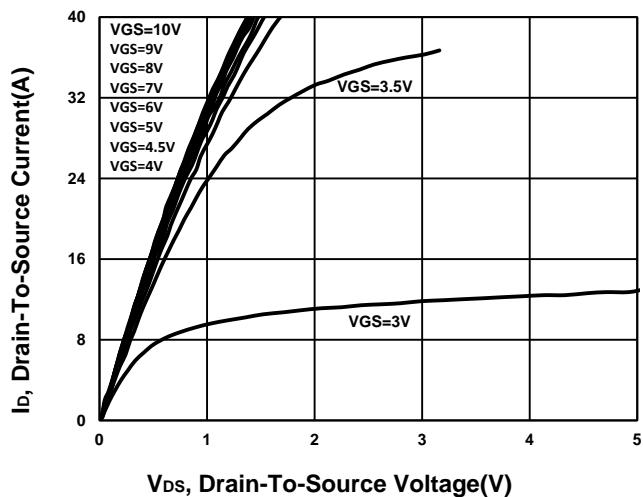
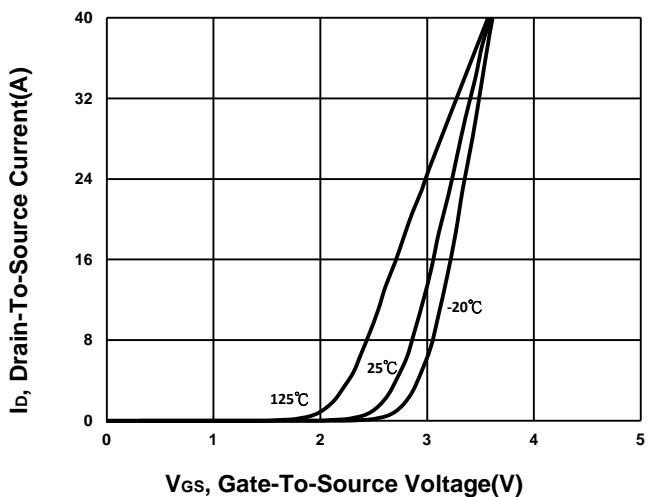
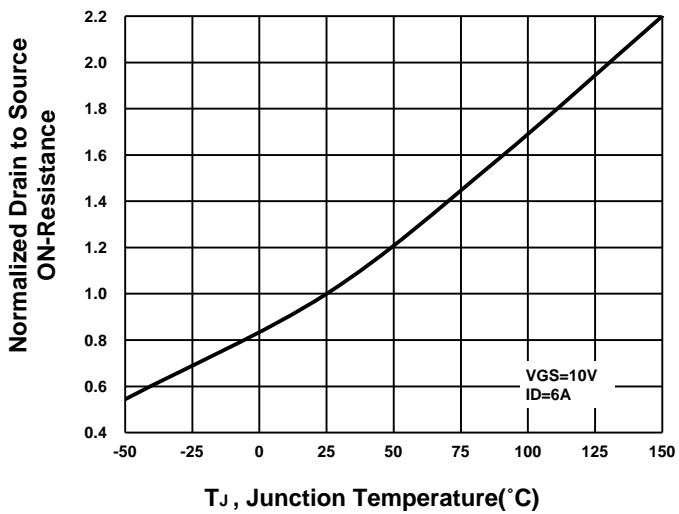
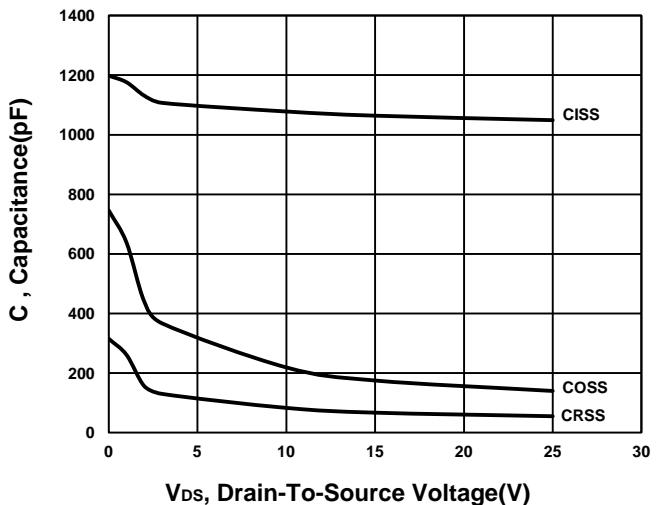
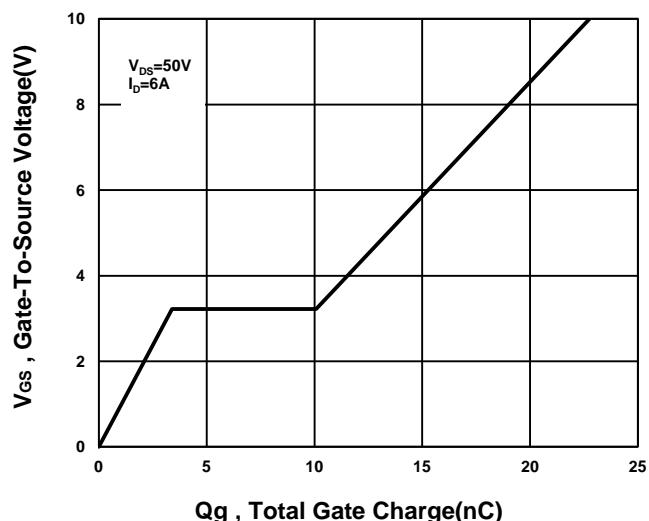
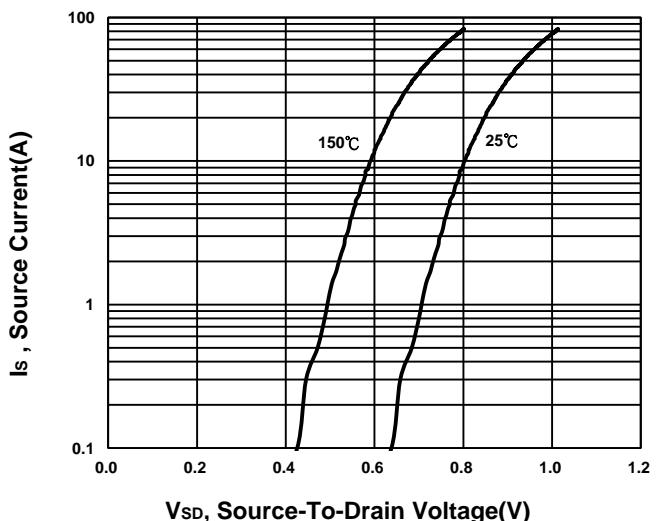
THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		46	°C / W
Junction-to-Case	$R_{\theta JC}$		2.5	

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 6\text{A}$		30	48	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 6\text{A}$		27	37	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 6\text{A}$		30		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		1049		pF
Output Capacitance	C_{oss}			140		
Reverse Transfer Capacitance	C_{rss}			56		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.3		Ω
Total Gate Charge ²	Q_g	$V_{\text{GS}} = 10\text{V}$		23		nC
				12.8		
Gate-Source Charge ²	Q_{gs}	$V_{\text{DS}} = 50\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 6\text{A}$		3.5		nS
Gate-Drain Charge ²	Q_{gd}			7.8		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$			32		
Rise Time ²	t_r			22		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$	$V_{\text{DS}} = 50\text{V}, I_D \approx 6\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$		46		nS
Fall Time ²	t_f			22		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S	$I_F = 6\text{A}, V_{\text{GS}} = 0\text{V}$			24	A
Forward Voltage ¹	V_{SD}				1.2	V
Reverse Recovery Time	t_{rr}			31		nS
Reverse Recovery Charge	Q_{rr}			35		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P3710BK
PDFN 5x6P
Halogen-Free & Lead-Free****Output Characteristics****Transfer Characteristics****On-Resistance VS Temperature****Capacitance Characteristic****Gate charge Characteristics****Source-Drain Diode Forward Voltage**

NIKO-SEM

**N-Channel Enhancement Mode
Field Effect Transistor**

P3710BK
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